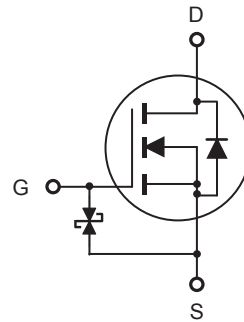
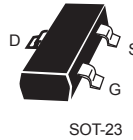


N-Channel Enhancement Mode Field Effect Transistor

FEATURES

- 20V, 6A, $R_{DS(ON)} = 22m\Omega$ @ $V_{GS} = 4.5V$.
 $R_{DS(ON)} = 31m\Omega$ @ $V_{GS} = 2.5V$.
- High dense cell design for extremely low $R_{DS(ON)}$.
- RoHS compliant.
- Rugged and reliable.
- SOT-23 package.
- ESD Protected 2KV.



ABSOLUTE MAXIMUM RATINGS $T_A = 25^\circ C$ unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	V_{DS}	20	V
Gate-Source Voltage	V_{GS}	± 8	V
Drain Current-Continuous	I_D	6	A
Drain Current-Pulsed ^a	I_{DM}	24	A
Maximum Power Dissipation	P_D	1.25	W
Operating and Store Temperature Range	T_J, T_{stg}	-55 to 150	$^\circ C$

Thermal Characteristics

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Ambient ^b	$R_{\theta JA}$	100	$^\circ C/W$

Electrical Characteristics $T_A = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	20			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 20V, V_{GS} = 0V$			1	μA
Gate Body Leakage Current, Forward	I_{GSSF}	$V_{GS} = 8V, V_{DS} = 0V$			10	μA
Gate Body Leakage Current, Reverse	I_{GSSR}	$V_{GS} = -8V, V_{DS} = 0V$			-10	μA
On Characteristics ^c						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS} = V_{DS}, I_D = 250\mu A$	0.6		0.9	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 4.5V, I_D = 3A$		17	22	$m\Omega$
		$V_{GS} = 2.5V, I_D = 2A$		24	31	$m\Omega$
Dynamic Characteristics ^c						
Input Capacitance	C_{iss}	$V_{DS} = 10V, V_{GS} = 0V,$ $f = 1.0\text{ MHz}$		535		pF
Output Capacitance	C_{oss}			125		pF
Reverse Transfer Capacitance	C_{rss}			70		pF
Switching Characteristics ^d						
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 10V, I_D = 1A,$ $V_{GS} = 4.5V, R_{GEN} = 6\Omega$		32		ns
Turn-On Rise Time	t_r			40		ns
Turn-Off Delay Time	$t_{d(off)}$			210		ns
Turn-Off Fall Time	t_f			105		ns
Total Gate Charge	Q_g	$V_{DS} = 10V, I_D = 5A,$ $V_{GS} = 4.5V$		6.4		nC
Gate-Source Charge	Q_{gs}			0.9		nC
Gate-Drain Charge	Q_{gd}			2.1		nC
Drain-Source Diode Characteristics and Maximum Ratings						
Drain-Source Diode Forward Current ^b	I_S				0.8	A
Drain-Source Diode Forward Voltage ^c	V_{SD}	$V_{GS} = 0V, I_S = 1A$			1.5	V
Notes : a. Repetitive Rating : Pulse width limited by maximum junction temperature. b. Surface Mounted on FR4 Board, $t \leq 10\text{ sec}$. c. Pulse Test : Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$. d. Guaranteed by design, not subject to production testing.						

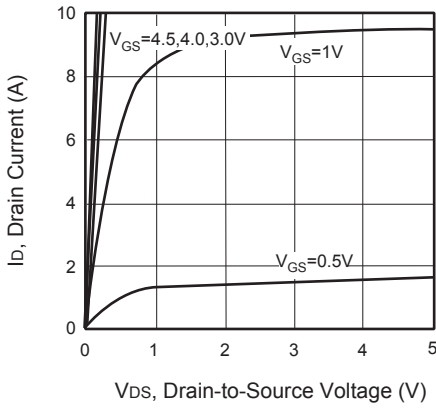


Figure 1. Output Characteristics

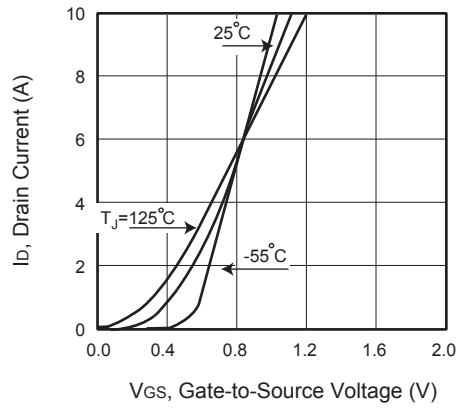


Figure 2. Transfer Characteristics

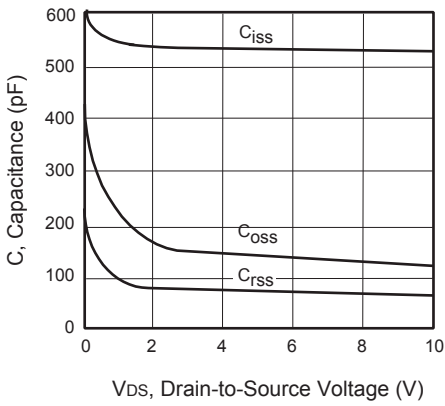


Figure 3. Capacitance

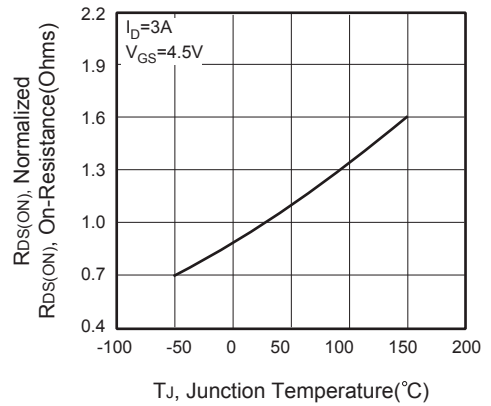


Figure 4. On-Resistance Variation with Temperature



Figure 5. Gate Threshold Variation with Temperature

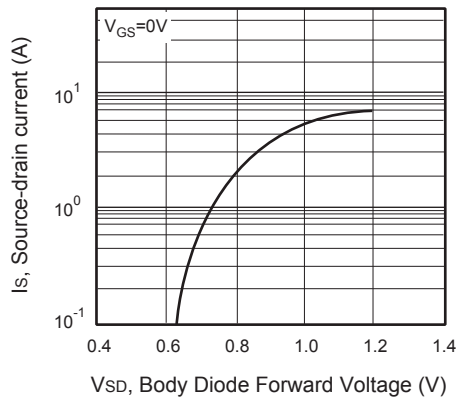


Figure 6. Body Diode Forward Voltage Variation with Source Current

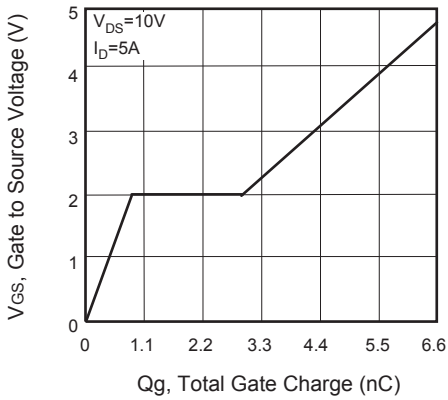


Figure 7. Gate Charge

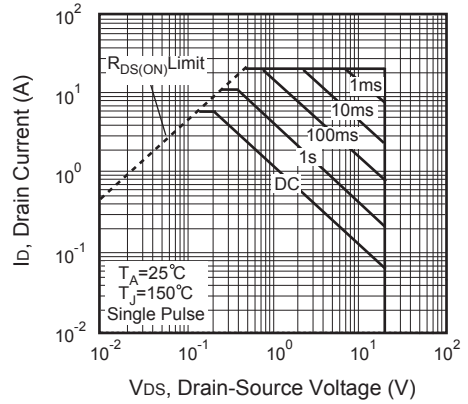


Figure 8. Maximum Safe Operating Area

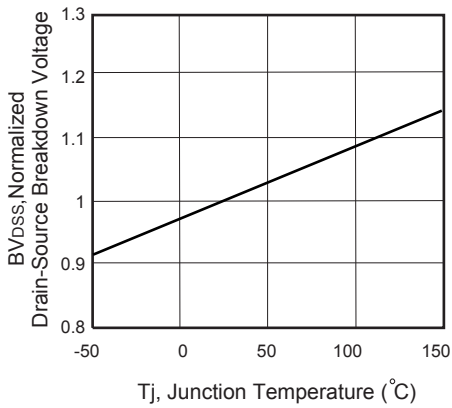


Figure 9. Breakdown Voltage Variation VS Temperature

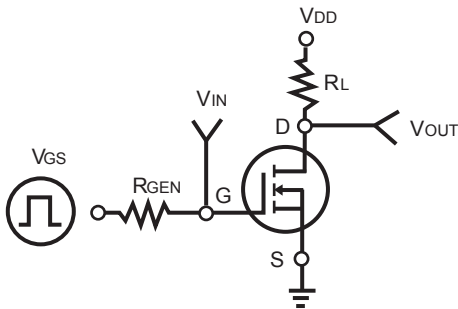


Figure 10. Switching Test Circuit

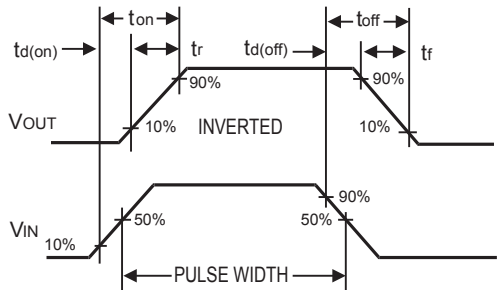


Figure 11. Switching Waveforms

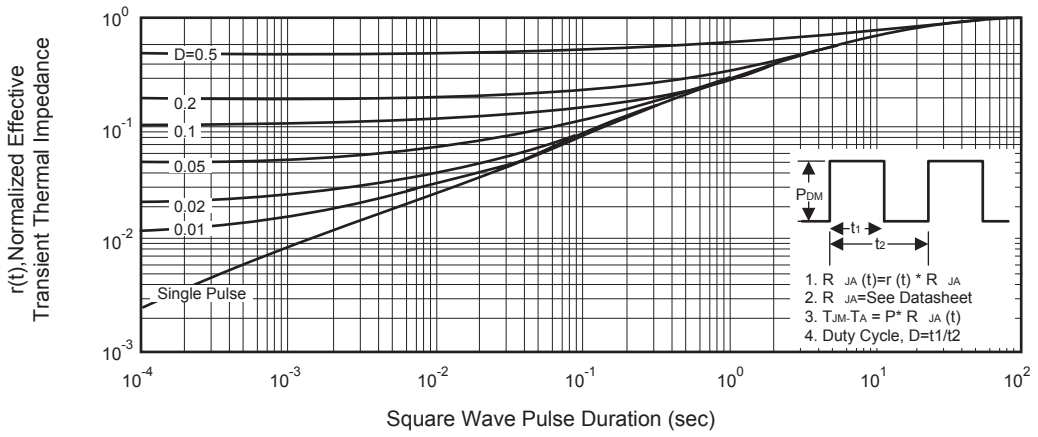
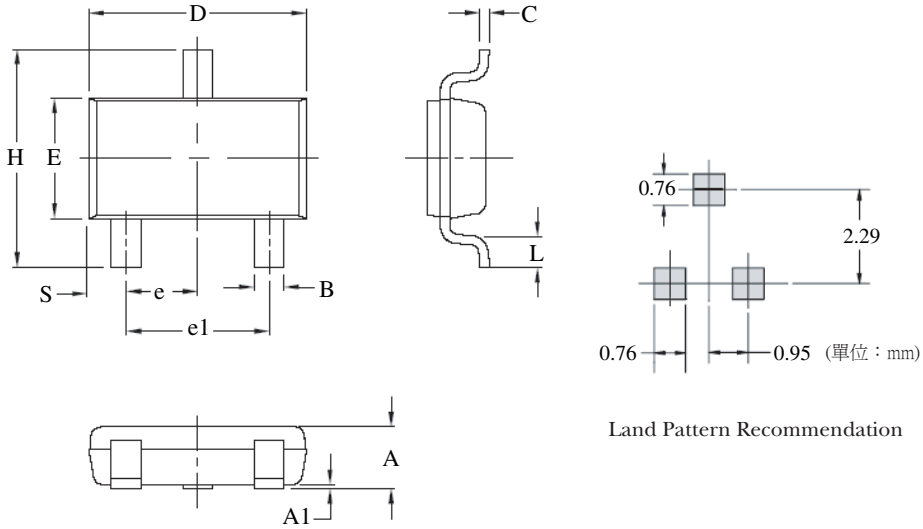


Figure 12. Normalized Thermal Transient Impedance Curve

TSOT-23 產品外觀尺寸圖 (Product Outline Dimension)



SYMBOLS	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	0.700	0.900	0.028	0.035
A1	0.000	0.100	0.000	0.004
B	0.300	0.500	0.012	0.020
C	0.085	0.200	0.003	0.008
D	2.72	3.040	0.107	0.120
E	1.400	1.800	0.055	0.071
e	0.95BSC		0.037BSC	
e1	1.780	2.180	0.070	0.086
H	2.500	3.100	0.098	0.122
L	0.35		0.55	
S	0.410	0.610	0.016	0.024